

Test report No.

Page

: 10697030H-A-R1 : 1 of 22 : March 25, 2015

Issued date Revised date FCC ID

: April 10, 2015 : E4EV640HAM11V2

RADIO TEST REPORT

Test Report No.: 10697030H-A-R1

Applicant

: OMRON Corporation

Type of Equipment

Carrier ID Reader/Writer (RFID)

Model No.

V640-HAM11-ETN-V2 (Amplifier Unit)

FCC ID

: E4EV640HAM11V2

Test regulation

FCC Part 15 Subpart C: 2015

Test Result

Complied

- 1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
- 2. The results in this report apply only to the sample tested.
- 3. This sample tested is in compliance with above regulation.
- 4. The test results in this report are traceable to the national or international standards.
- 5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
- 6. This test report covers Radio technical requirements. It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)
- 7. This report is a revised version of 10697030H-A. 10697030H-A is replaced with this report.

Date of test:

March 12 to 18, 2015

Representative test engineer:

Kazuya Yoshioka Engineer

Consumer Technology Division

Approved by:

Pakayuki Shimada Engineer

Consumer Technology Division



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.

*As for the range of Accreditation in NVLAP, you may refer to the WEB address,

http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap

UL Japan, Inc.

Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone

: +81 596 24 8999

Facsimile : +81 596 24 8124

13-EM-F0429

 Test report No.
 : 10697030H-A-R1

 Page
 : 2 of 22

 Issued date
 : March 25, 2015

 Revised date
 : April 10, 2015

 FCC ID
 : E4EV640HAM11V2

REVISION HISTORY

Original Test Report No.: 10697030H-A

Revision	Test report No.	Date	Page revised	Contents
- (Original)	10697030H-A	March 25, 2015	-	-
1	10697030H-A-R1	April 10, 2015	P. 5	Correction: Detector of the worst margin for Electric Field Strength of Fundamental Emission in clause 3.2
1	10697030H-A-R1	April 10, 2015	P. 9	Correction of name of antenna in Clause 4.2
1	10697030H-A-R1	April 10, 2015	P. 15	Correction of data for Radiated Emission below 30MHz (Fundamental and Spurious Emission) in APPENDIX 1

UL Japan, Inc. Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No.
Page

: 10697030H-A-R1 : 3 of 22 : March 25, 2015

Issued date Revised date FCC ID : March 25, 2015 : April 10, 2015 : E4EV640HAM11V2

CONTENTS	PAGE
SECTION 1: Customer information	4
SECTION 2: Equipment under test (E.U.T.)	4
SECTION 3: Test specification, procedures & results	
SECTION 4: Operation of E.U.T. during testing	
SECTION 5: Conducted Emission	
SECTION 6: Radiated emission (Fundamental and Spurious Emission)	
SECTION 7: -26dB Bandwidth	
SECTION 8: 99% Occupied Bandwidth	
APPENDIX 1: Data of EMI test	
Conducted Emission	14
Radiated Emission below 30MHz (Fundamental and Spurious Emission)	
Radiated Emission above 30MHz (Spurious Emission)	
-26dB Bandwidth and 99% Occupied Bandwidth	
APPENDIX 2: Test instruments	
APPENDIX 3: Photographs of test setup	
Conducted Emission	
Radiated Emission	
Worst Case Position	

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 4 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

SECTION 1: Customer information

Company Name : OMRON Corporation

Address : 2-2-1, NISHI-KUSATSU, KUSATSU-CITY, SHIGA-PREF., 525-0035

JAPAN

Telephone Number : +81-77-565-5287 Facsimile Number : +81-77-565-5569 Contact Person : Hiroaki Motoshima

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Carrier ID Reader/Writer (RFID)

Model No. : V640-HAM11-ETN-V2 (Amplifier Unit)

Serial No. : Refer to Section 4, Clause 4.2

Rating : DC 24V

Receipt Date of Sample : February 24, 2015

Country of Mass-production : Japan

Condition of EUT : Production prototype

(Not for Sale: This sample is equivalent to mass-produced items.)

Modification of EUT : No Modification by the test lab

2.2 Product Description

General Specification

Clock frequency(ies) in the system : 8MHz (for both types), 125MHz (EtherNet Communication type only)

Radio Specification

Radio Type : Transceiver Frequency of Operation : 134.2 kHz

Modulation : Amplitude Shift Keying

Power Supply (radio part input) : DC 5V

Antenna type : Loop Coil Antenna

Similar model

This EUT has similar model: V640-HAM11-V4.

- V640-HAM11-ETN-V2: EtherNet Communication type and Normal distance type
- V640-HAM11-V4: Serial Communication type and Normal distance type

There is no difference except for these.

UL Japan, Inc. Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 5 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2015, final revised on January 21, 2015

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators

Section 15.207 Conducted Emission

Section 15.209 Radiated emission limits, general requirements

FCC Part 15.31 (e)

This EUT provides stable voltage (DC 5V) constantly to RF Module regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

The EUT has an external antenna connector, but it is installed by the professionals. Therefore, the equipment complies with the antenna requirement of Section 15.203.

3.2 Procedures and results

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	Conducted Emission	<fcc> ANSI C63.4:2009 7. AC powerline conducted emission measurements <ic> RSS-Gen 8.8</ic></fcc>	<fcc> Section 15.207 <ic> RSS-Gen 8.8</ic></fcc>	-	N/A	[QP] 10.4dB 6.15480MHz, L [AV] 0.4dB 0.47780MHz, L	Complied
2	Electric Field Strength of Fundamental Emission	<fcc> ANSI C63.4:2009 13. Measurement of intentional radiators <ic> RSS-Gen 6.4, 6.12</ic></fcc>	<fcc> Section 15.209 <ic> RSS-210 2.5.1 RSS-Gen 8.9</ic></fcc>	Radiated	N/A	12.2dB 0.13420MHz 0 deg., PK (PK with Duty factor)	Complied
3	Electric Field Strength of Spurious Emission	<fcc> ANSI C63.4:2009 13. Measurement of intentional radiators <ic> RSS-Gen 6.4, 6.13</ic></fcc>	<fcc> Section 15.209 <ic> RSS-210 2.5.1 RSS-Gen 8.9</ic></fcc>	Radiated	N/A	2.5dB 58.781MHz, Vertical, QP	Complied
4	-26dB Bandwidth	<fcc> ANSI C63.4:2009 13. Measurement of intentional radiators <ic></ic></fcc>	<fcc> Reference data <ic> -</ic></fcc>	Radiated	N/A	N/A	N/A
Note	e: UL Japan, Inc.'s EMI	Work Procedures No. 1	3-EM-W0420 and	113-EM-W	/0422.		

,

UL Japan, Inc. Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

^{*} The EUT complies with FCC Part 15 Subpart B: 2014, final revised on December 23, 2014.

: 10697030H-A-R1 Test report No.

Page

: 6 of 22 Issued date : March 25, 2015 Revised date : April 10, 2015 FCC ID : E4EV640HAM11V2

3.3 Addition to standard

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied	RSS-Gen 6.6	-	Radiated	N/A	N/A	N/A
	Band Width						

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission
(semi-	(<u>+</u> dB)
anechoic	150kHz-30MHz
chamber)	
No.1	3.5dB
No.2	3.5dB
No.3	3.4dB
No.4	3.5dB

Test room		Radiated emission							
(semi-		(3m*)	(<u>+</u> dB)		(1m*))(<u>+</u> dB)	$(0.5\text{m}^*)(\underline{+}\text{dB})$		
anechoic	9kHz	30MHz	300MHz	1GHz	10GHz	18GHz	26.5GHz		
chamber)	-30MHz	-300MHz	-1GHz	-10GHz	-18GHz	-26.5GHz	-40GHz		
No.1	4.3dB	5.5dB	6.3dB	5.5dB	5.8dB	5.8dB	4.3dB		
No.2	4.2dB	5.4dB	6.3dB	5.4dB	5.7dB	5.9dB	5.6dB		
No.3	4.4dB	5.4dB	6.4dB	5.2dB	5.5dB	5.8dB	5.5dB		
No.4	4.7dB	5.6dB	6.4dB	5.3dB	5.7dB	5.9dB	5.5dB		

^{*3}m/1m/0.5m = Measurement distance

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

Radiated emission test (3m)

[Electric Field Strength of Fundamental Emission]

The data listed in this test report has enough margin, more than the site margin.

[Electric Field Strength of Spurious Emission]

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 7 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

3.5 Test Location

UL Japan, Inc. Ise EMC Lab. *NVLAP Lab. code: 200572-0 4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone: +81 596 24 8999 Facsimile: +81 596 24 8124

	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	8.0 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	6.2 x 4.7 x 3.0m	4.8 x 4.6m	-

^{*} Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

Refer to APPENDIX.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 8 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

SECTION 4: Operation of E.U.T. during testing

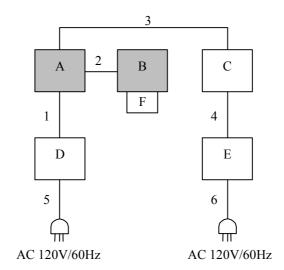
4.1 Operating Modes

Test mode	Remarks				
Transmitting 134.2kHz With Tag mode	*1)				
PC Software: UcomV640					
Version: 1.0.0.0					
The EUT does not have a Power Control function.					
The test was performed with a fixed value.					
Mass-produced product will have same level as it					

^{*1)} This EUT has two modes which Tag is attached to the EUT or not. The worst case was confirmed with and without Tag, as a result, the test with Tag was the worst case. Therefore the test with Tag was performed only.

Justification : The system was configured in typical fashion (as a customer would normally use it) for testing.

4.2 Configuration and peripherals



^{*} Cabling and setup were taken into consideration and test data was taken under worse case conditions.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 9 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

Description of EUT and Support equipment

No.	Item	Model number	Serial	Manufacturer	Remarks
			number		
A	Carrier ID Reader/Writer	V640-HAM11-ETN-V2	5	OMRON Corporation	EUT
	(RFID)	(Amplifier Unit)			
В	CIDRW Head (Antenna)	V640-HS61	8	OMRON Corporation	EUT
C	Switching HUB	W4S1-05B	17310K	OMRON Corporation	-
D	Power Supply	S8VS-01524	-	OMRON Corporation	-
Е	Power Supply	S8VS-03024	-	OMRON Corporation	-
F	Tag	RI-TRP-DR2B-30	1	OMRON Corporation	-

List of cables used

List U	Dist of Cables used								
No.	Name	Length (m)	Shi	Remark					
			Cable	Connector					
1	DC Cable	2.0	Unshielded	Unshielded	-				
2	Antenna Cable	2.0	Shielded	Shielded	-				
3	LAN Cable	5.0	Shielded	Shielded	-				
4	DC Cable	0.6	Unshielded	Unshielded	-				
5	AC Cable	1.9	Unshielded	Unshielded	-				
6	AC Cable	1.9	Unshielded	Unshielded	-				

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 10 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cable and AC cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber or a Measurement Room.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

Detector : QP CISPR AV detector (IF BW 9 kHz)

Measurement range : 0.15-30MHz Test data : APPENDIX 1

Test result : Pass

Date: March 14, 2015 Test engineer: Kazuya Yoshioka

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 11 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

SECTION 6: Radiated emission (Fundamental and Spurious Emission)

Test Procedure

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

Frequency: From 9kHz to 30MHz

The EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for vertical polarization (antenna angle: 0deg., 45deg., 90deg., 135deg., and 180deg.) and horizontal polarization.

*Refer to Figure 1 about Direction of the Loop Antenna.

Frequency: From 30MHz to 1GHz

The measuring antenna height varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization.

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency		Below 30MHz	30MHz to 300MHz	300MHz to 1GHz
	Antenna Type	Loop	Biconical	Logperiodic

Frequency	From 9kHz to 90kHz and From 110kHz to 150kHz	From 90kHz to 110kHz	From 150kHz to 490kHz	From 490kHz to 30MHz	From 30MHz to 1GHz		
Instrument used		Т	est Receiver	st Receiver			
Detector	PK/AV	QP	PK/AV	QP	QP		
IF Bandwidth	200Hz	200Hz	9kHz	9kHz	120kHz		
Test Distance	3m *1)	3m *1)	3m *1)	3m *2)	3m		

^{*1)} Distance Factor: $40 \times \log (3m/300m) = -80dB$

Although these tests were performed other than open field test site, adequate comparison measurements were confirmed against 30 m open field test site. Therefore sufficient tests were made to demonstrate that the alternative site produces results that correlate with the ones of tests made in an open field based on KDB 937606.

These tests were performed in semi anechoic chamber. Therefore the measured level of emissions may be higher than if measurements were made without a ground plane.

However test results were confirmed to pass against standard limit.

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

This EUT has two modes which Tag is attached to the EUT or not. The worst case was confirmed with and without Tag, as a result, the test with Tag was the worst case. Therefore the test with Tag was performed only.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 9kHz-1GHz Test data : APPENDIX 1

Test result : Pass

Date: March 12, 2015 Test engineer: Kazuya Yoshioka March 13, 2015 Kenshi Shimomura

UL Japan, Inc. Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

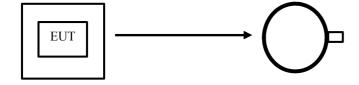
^{*2)} Distance Factor: $40 \times \log (3m/30m) = -40dB$

Test report No. : 10697030H-A-R1
Page : 12 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

Figure 1: Direction of the Loop Antenna

EUT EUT

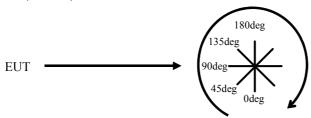
Top View (Horizontal)



Antenna was not rotated.

.....

Top View (Vertical)



Front side: 0 deg.

Forward direction: clockwise

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 13 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

SECTION 7: -26dB Bandwidth

Test Procedure

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test	Span	RBW	VBW	Sweep	Detector	Trace	Instrument used
-26dB Bandwidth	100kHz	1kHz	3kHz	Auto	Peak	Max Hold	Spectrum Analyzer

Test data : APPENDIX 1

Test result : Pass

SECTION 8: 99% Occupied Bandwidth

Test Procedure

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test	Span	RBW	VBW	Sweep	Detector	Trace	Instrument used				
99% Occupied Bandwidth Enough width to display Bandwidth Enough width to display -26dB Bandwidth 1kHz Three times of RBW Auto Peak *1) Max Hold Spectrum Analyzer 1											
,	*1) The measurement was performed with Peak detector, Max Hold since the duty cycle was not 100%. Peak hold was applied as Worst-case measurement.										

Test data : APPENDIX 1

Test result : Pass

UL Japan, Inc. Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1 Page : 14 of 22 **Issued date** : March 25, 2015 : April 10, 2015 Revised date FCC ID : E4EV640HAM11V2

APPENDIX 1: Data of EMI test

Conducted Emission

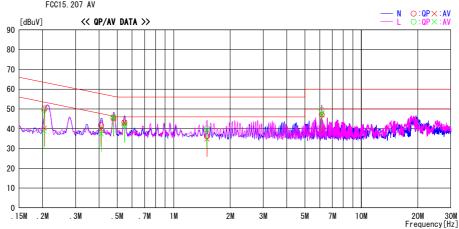
DATA OF CONDUCTED EMISSION TEST

Ise EMC Lab. No.2 Semi Anechoic Chamber Date: 2015/03/14

Report No. : 10697030H

23deg. C['] / 39% RH Kazuya Yoshioka Temp./Humi. Engineer

Mode / Remarks : Tx 134.2kHz with tag



Technology QP				Mar		Lin		Resi	Corr.		Reading	Frequency
0. 20511 27. 2 17. 3 23. 0 50. 2 40. 3 63. 4 53. 4 13. 2 13. 1 N 2 41. 7 39. 8 57. 7 47. 7 16. 0 7. 9 N 0 4.04980 18. 8 16. 9 22. 9 45. 3 45. 2 56. 4 46. 4 11. 1 1. 2 N 1 1 1. 2 N 1 1 1. 2 N 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	Comment	Phase										
0. 40980			[dB]	[dB]	[dBuV]	[dBuV]	[dBuV]				[dBuV]	[MHz]
0. 47781 22. 4 22. 3 22. 9 45. 3 45. 2 56. 4 46. 4 11. 1 1. 2 N 0. 54630 20. 3 20. 4 22. 8 43. 1 43. 2 56. 0 46. 0 12. 9 2. 8 N 1. 50360 13. 2 11. 8 23. 0 36. 2 34. 8 56. 0 46. 0 19. 8 11. 2 N 6. 15780 23. 6 23. 4 23. 5 47. 1 46. 9 60. 0 50. 0 12. 9 3. 1 N 0. 20375 26. 4 15. 9 23. 0 49. 4 38. 9 63. 5 53. 5 14. 1 14. 6 L 0. 41161 16. 6 14. 5 22. 9 39. 5 37. 4 57. 6 47. 6 18. 1 10. 2 L 0. 47780 22. 9 23. 1 22. 9 45. 8 46. 0 56. 4 46. 4 10. 6 0. 4 L 0. 54655 19. 2 19. 2 22. 8 42. 0 42. 0 56. 0 46. 0 14. 0 4. 0 L 1. 50280 17. 2 16. 4 23. 0 40. 2 39. 4 56. 0 46. 0 15. 8 6. 6 6. 6 L		N	13. 1	13. 2		63. 4	40. 3	50. 2			27. 2	0. 20511
0.54630		N	7. 9	16.0	47. 7	57. 7		41. 7	22. 9	16.9	18. 8	0. 40980
1. 50360 13. 2 11. 8 23. 0 36. 2 34. 8 56. 0 46. 0 19. 8 11. 2 N 6. 15780 23. 6 23. 4 23. 5 47. 1 46. 9 60. 0 50. 0 12. 9 3. 1 N 0. 20375 26. 4 15. 9 23. 0 49. 4 38. 9 63. 5 53. 5 14. 1 14. 6 L 0. 41161 16. 6 14. 5 22. 9 39. 5 37. 4 57. 6 47. 6 18. 1 10. 2 L 0. 47780 22. 9 23. 1 22. 9 45. 8 46. 0 56. 4 46. 4 10. 6 0. 4 L 0. 54655 19. 2 19. 2 22. 8 42. 0 42. 0 56. 0 46. 0 15. 8 6. 6 L		N	1.2	11.1	46. 4	56. 4	45. 2	45. 3	22. 9	22. 3	22. 4	0. 47781
6. 15780 23. 6 23. 4 23. 5 47. 1 46. 9 60. 0 50. 0 12. 9 3. 1 N 0. 20375 26. 4 15. 9 23. 0 49. 4 38. 9 63. 5 53. 5 14. 1 14. 6 L 0. 41161 16. 6 14. 5 22. 9 39. 5 37. 4 57. 6 47. 6 18. 1 10. 2 L 0. 47780 22. 9 23. 1 22. 9 45. 8 46. 0 56. 4 46. 4 10. 6 0. 4 L 0. 54655 19. 2 19. 2 22. 8 42. 0 42. 0 56. 0 46. 0 14. 0 4. 0 L 1. 50280 17. 2 16. 4 23. 0 40. 2 39. 4 56. 0 46. 0 15. 8 6. 6 L		N	2.8	12. 9	46. 0	56.0	43. 2	43. 1	22. 8	20. 4	20. 3	0.54630
0. 20375 26. 4 15. 9 23. 0 49. 4 38. 9 63. 5 53. 5 14. 1 14. 6 L 0. 41161 16. 6 14. 5 22. 9 39. 5 37. 4 57. 6 47. 6 18. 1 10. 2 L 0. 47780 22. 9 23. 1 22. 9 45. 8 46. 0 56. 4 46. 4 10. 6 0. 4 L 0. 54655 19. 2 19. 2 22. 8 42. 0 42. 0 56. 0 46. 0 14. 0 4. 0 4. 0 1. 50280 17. 2 16. 4 23. 0 40. 2 39. 4 56. 0 46. 0 15. 8 6. 6 L		N	11.2	19.8	46. 0	56.0	34. 8		23. 0	11.8	13. 2	1.50360
0.41161		N	3.1	12. 9	50.0	60.0	46. 9	47. 1	23. 5	23. 4	23. 6	6. 15780
0.4780 22.9 23.1 22.9 45.8 46.0 56.4 46.4 10.6 0.4 L 0.54655 19.2 19.2 22.8 42.0 42.0 56.0 46.0 14.0 4.0 L 1.50280 17.2 16.4 23.0 40.2 39.4 56.0 46.0 15.8 6.6 L		L	14.6	14. 1	53. 5	63. 5	38. 9	49. 4	23. 0	15. 9	26. 4	0. 20375
0.54655 19.2 19.2 22.8 42.0 42.0 56.0 46.0 14.0 4.0 L 1.50280 17.2 16.4 23.0 40.2 39.4 56.0 46.0 15.8 6.6 L		L	10.2	18. 1	47. 6	57. 6	37. 4	39. 5	22. 9	14. 5	16. 6	0. 41161
1.50280 17.2 16.4 23.0 40.2 39.4 56.0 46.0 15.8 6.6 L		L	0.4	10.6	46. 4	56. 4	46. 0	45. 8	22. 9	23. 1	22. 9	0. 47780
		L	4.0	14. 0	46. 0	56.0	42. 0	42. 0	22. 8	19. 2	19. 2	0. 54655
6. 15480 26. 1 24. 1 23. 5 49. 6 47. 6 60. 0 50. 0 10. 4 2. 4 L		L	6.6	15. 8	46. 0	56.0	39. 4	40. 2	23. 0	16.4	17. 2	1.50280
		L	2.4	10.4	50.0	60.0	47. 6	49. 6	23. 5	24. 1	26. 1	6. 15480

UL Japan, Inc. Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

^{*}The test result is rounded off to one or two decimal places, so some differences might be observed.

Test report No. : 10697030H-A-R1
Page : 15 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

Radiated Emission below 30MHz (Fundamental and Spurious Emission)

Test place Ise EMC Lab. No.2 Semi Anechoic Chamber

Report No. 10697030H Date 03/13/2015

Temperature/ Humidity
Engineer
Mode

20 deg. C / 30% RH
Kenshi Shimomura
Tx 134.2kHz

PK or QP

Ant Deg [deg]	Frequency	Detector	Reading	Ant	Loss	Gain	Duty	Result	Limit	Margin	Remark
				Factor			Factor				
	[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	
0	0.13420	PK	67.1	19.6	-73.9	0.0	-	12.8	45.0	32.2	Fundamental
0	0.26840	PK	24.9	19.6	-73.9	0.0	-	-29.4	39.0	68.4	
0	0.40260	PK	28.4	19.6	-73.9	0.0	-	-25.9	35.5	61.4	
0	0.53680	QP	15.5	19.5	-33.9	0.0	-	1.1	33.0	31.9	
0	0.67100	QP	17.7	19.5	-33.8	0.0	-	3.4	31.1	27.7	
0	0.80520	QP	15.3	19.5	-33.8	0.0	-	1.0	29.5	28.5	
0	0.93940	QP	11.9	19.5	-33.8	0.0	-	-2.4	28.1	30.5	
0	1.07360	QP	10.5	19.5	-33.8	0.0	-	-3.8	26.9	30.7	
0	1.20780	QP	7.9	19.5	-33.8	0.0	-	-6.4	25.9	32.3	
0	1.34200	QP	9.3	19.5	-33.7	0.0	-	-4.9	25.0	29.9	

Result = Reading + Ant Factor + Loss (Cable + Attenuator + Filter + D.Factor) - Gain(Amprifier)

PK with Duty factor

1	Ant Deg [deg]	Frequency	Detector	Reading	Ant	Loss	Gain	Duty	Result	Limit	Margin	Remark
	C 1 C3	1 ,		Ü	Factor			Factor			Ü	
		[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	
	0	0.13420	PK	67.1	19.6	-73.9	0.0	0.0	12.8	25.0	12.2	
	0	0.26840	PK	24.9	19.6	-73.9	0.0	0.0	-29.4	19.0	48.4	
	0	0.40260	PK	28.4	19.6	-73.9	0.0	0.0	-25.9	15.5	41.4	

Result = Reading + Ant Factor + Loss (Cable + Attenuator + Filter + D.Factor) - Gain(Amprifier) + Duty factor *

Result of the fundamental emission at 3m without Distance factor

PK or QP

Ant Deg [deg]	Frequency	Detector	Reading	Ant	Loss	Gain	Duty	Result	Limit	Margin	Remark
				Factor			Factor				
	[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	
0	0.13420	PK	67.1	19.6	6.1	0.0	-	92.8	-	-	Fundamental

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter) - Gain(Amprifier)

UL Japan, Inc. Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

^{*} Since the peak emission result satisfied the average limit, the peak emission result with Duty Factor was calculated as Duty 100%.

^{*} All spurious emissions lower than this result.

Test report No. : 10697030H-A-R1
Page : 16 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

Radiated Emission above 30MHz (Spurious Emission)

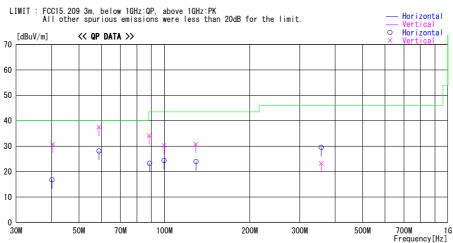
DATA OF RADIATED EMISSION TEST UL Japan, Inc. Ise EMC La

UL Japan, Inc. Ise EMC Lab. No.2 Semi Anechoic Chamber Date: 2015/03/12

Report No. : 10697030H

Temp./Humi. : 21deg. C / 39% RH Engineer : Kazuya Yoshioka

Mode / Remarks : Tx 134.2kHz Worst-axis(Ant Hori:Z Vert:Z ECU Hori:X Vert:X) with tag



Frequency	Reading	DET	Antenna Factor	Loss& Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
40. 142	49. 2	QP	14. 4	-46.8	16.8	0	265	Hori.	40.0	23. 2	
40.394	63.3	QP	14. 3	-46.8	30.8	0	100	Vert.	40.0	9. 2	
58. 781	76.3	QP	7.8	-46.6	37. 5	93	100	Vert.	40.0	2. 5	
58. 781	66. 9	QP	7.8	-46.6	28. 1	350	374	Hori.	40.0	11.9	
88. 737	61.4	QP	8.3	-46. 4	23. 3	349	206	Hori.	43. 5	20. 2	
88. 376	72.3	QP	8. 2	-46. 4	34. 1	290	100	Vert.	43. 5	9.4	
99. 723	66.5	QP	10. 1	-46. 3	30. 3	274	100	Vert.	43. 5	13. 2	
99. 715	60.5	QP	10.1	-46. 3	24. 3	0	287	Hori.	43. 5	19. 2	
129. 432	56.3	QP	13. 5	-45. 9	23. 9	334	153	Hori.	43. 5	19.6	
128. 972	63. 2	QP	13. 5	-45. 9	30. 8	331	100	Vert.	43. 5	12. 7	
357. 604	57.3	QP	16.4	-44. 2	29. 5	165	100	Hori.	46. 0	16.5	
357. 443	51.0	QP	16.4	-44. 2	23. 2	146	100	Vert.	46. 0	22. 8	

*The test result is rounded off to one or two decimal places, so some differences might be observed.

UL Japan, Inc. Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 17 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

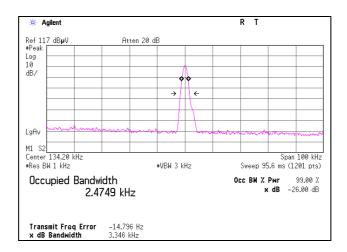
-26dB Bandwidth and 99% Occupied Bandwidth

Report No. 10697030H Test place Ise EMC Lab. Semi Anechoic Chamber No.3

Semi Anechoic Chamber No.3
Date 03/18/2015

Temperature / Humidity 23 deg. C / 44 % RH Engineer Takumi Shimada Mode Tx 134.2 kHz

-26dB Bandwidth	99% Occupied Bandwidth				
[kHz]	[kHz]				
3.346	2.4749				



4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 10697030H-A-R1
Page : 18 of 22
Issued date : March 25, 2015
Revised date : April 10, 2015
FCC ID : E4EV640HAM11V2

APPENDIX 2: Test instruments

EMI test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-02	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-06902	RE/CE	2014/06/25 * 12
MOS-22	Thermo-Hygrometer	Custom	CTH-201	0003	RE/CE	2015/01/13 * 12
MJM-14	Measure	KOMELON	KMC-36	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MSA-14	Spectrum Analyzer	Agilent	E4440A	MY48250080	RE/CE	2014/10/17 * 12
MTR-03	Test Receiver	Rohde & Schwarz	ESCI	100300	RE/CE	2014/06/03 * 12
MBA-02	Biconical Antenna	Schwarzbeck	BBA9106	VHA91032008	RE	2014/10/18 * 12
MLA-02	Logperiodic Antenna	Schwarzbeck	USLP9143	201	RE	2014/10/18 * 12
MCC-12	Coaxial Cable	Fujikura/Agilent	-	-	RE	2015/02/06 * 12
MAT-02	Attenuator	Weinschel Corp	2	BL0968	RE	2014/11/11 * 12
MPA-15	Pre Amplifier	SONOMA INSTRUMENT	315	260698	RE	2014/06/16 * 12
MLPA-01	Loop Antenna	Rohde & Schwarz	HFH2-Z2	100017	RE	2014/10/04 * 12
MCC-13	Coaxial Cable	Fujikura	3D-2W(12m)/5D- 2W(5m)/5D- 2W(0.8m)/5D-2W(1m)	-	RE	2015/02/06 * 12
MCC-143	Coaxial Cable	UL Japan	-	-	RE	2014/07/28 * 12
MAT-68	Attenuator	Anritsu	MP721B	6200961025	RE	2014/11/11 * 12
MLS-25	LISN(AMN)	Schwarzbeck	NSLK8127	8127-731	CE(EUT)	2014/07/09 * 12
MLS-26	LISN(AMN)	Schwarzbeck	NSLK8127	8127-732	CE(AE)	2014/07/09 * 12
MTA-28	Terminator	TME	CT-01	-	CE	2014/11/26 * 12
MAT-65	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2015/01/29 * 12
MHF-24	High Pass Filter 0.15- 30MHz	Rohde & Schwarz	EZ-25/3	100041	CE	2015/02/19 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted Emission RE: Spurious emission

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN